

# Search Notes



Application/Control No.

10/817,417

Examiner

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Applicant(s)/Patent under Reexamination

YUE ET AL.

Art Unit

1765

## SEARCHED

Class	Subclass	Date	Examiner
438	706	12/20/2005	KCC
	714		
	715		
438	723		
216	63		
216	74	12/20/05	KCC

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East Key words search USPAT. uspg. pub. Epo, JPO, IBM TDB. Derwent, inventor search	12/20/2005	KCC